

DATA SHEET

Model MHFS64815

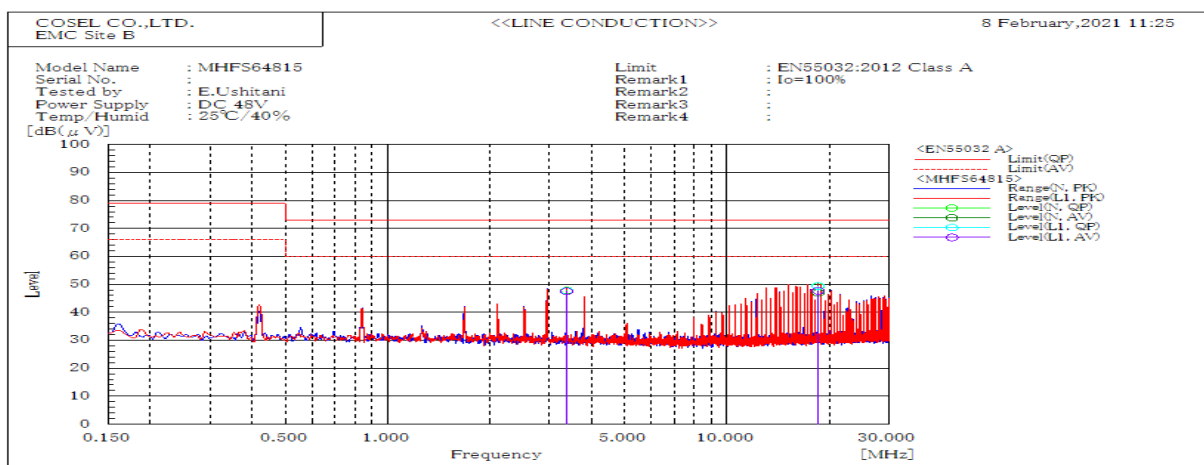
Date 05-Nov-21

Test EMI
Line conduction & Radiated emission

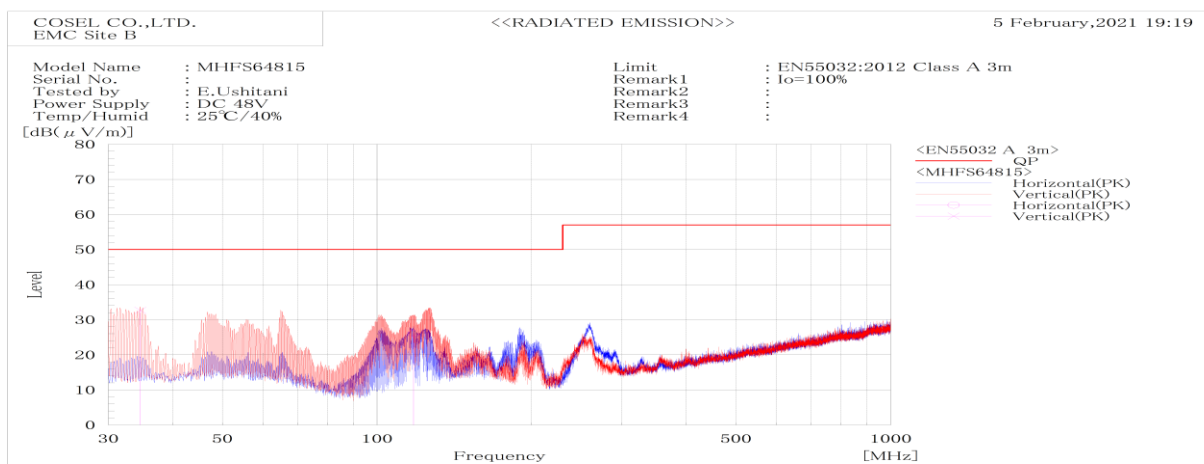
Temp. 25 degreeC

Humid. 40 %RH

Tested by E.Ushitani



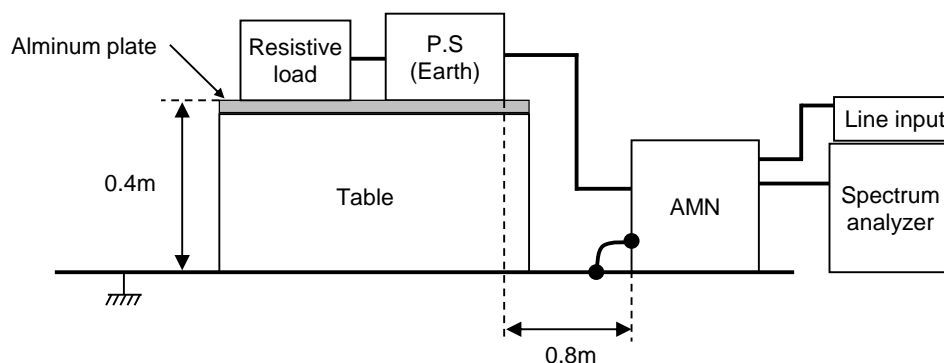
Frequency MHz	Line	Level dB(μV)	Limit dB(μV)	Margin dB	Pass/Fail	Remark
		QP	AV	QP	AV	
3.374	N	47.8	47.7	73	60	25.2 12.3 Pass
18.559	N	49.3	47	73	60	23.7 13 Pass
3.374	L1	47.6	47.5	73	60	25.4 12.5 Pass
18.556	L1	49.5	47.7	73	60	23.5 12.3 Pass



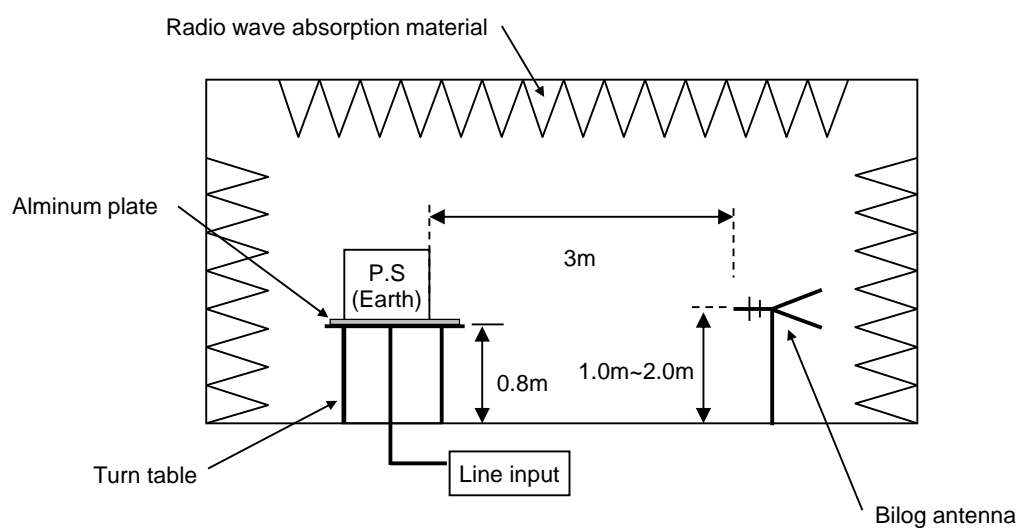
Frequency MHz	Polarization	Stability	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
117.813	H	Stable	26.1	50	23.9	Pass	199.7	0	
34.62	V	Stable	32.7	50	17.3	Pass	100	0	

DATA SHEET		Date	05-Nov-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

1. Line conduction



2. Radiated emission

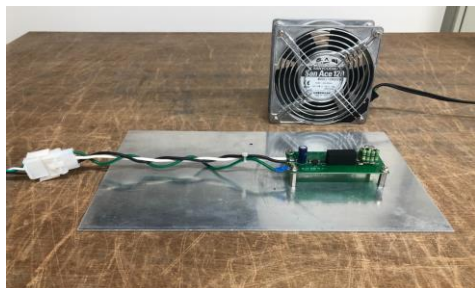


Conditions

Test : EMI
Model Name: MHFS6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

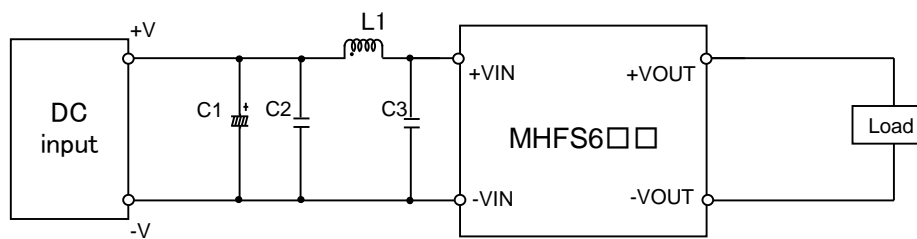


Fig.1 Testing circuitry

C1 :	MHFS612□□	50V 100 μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS624□□	-
	MHFS648□□	-
C2 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS612□□	2600mA 2.2 μ H Inductor (LQH5BPN2R2NT0 MURATA MANUFACTURING)
	MHFS624□□	1600mA 10 μ H Inductor (LQH5BPN100MT0 MURATA MANUFACTURING)
	MHFS648□□	1050mA 22 μ H Inductor (LQH5BPN220MT0 MURATA MANUFACTURING)